IN THE SPECIFICATION

Rewrite the paragraph starting with "Still referring to FIG. 4" on page 13 as the following:

--Still referring to FIG. 4, the trim determination circuitry 324 includes a test current mirror transistor 340, a measurable zener diode Z32, and a determination amplifier ~~342~~344. The gate of the test current mirror transistor 340 couples with the output 334 of the replicate amplifier 330 such that the gate to source voltage of the test current mirror transistor 340 is substantially equal to the gate to source voltage of the adjustable test current source transistor 332, resulting in a scaled determination or test current ϵI_{2t} which is directly proportional to the adjustable test current αI_2 by a scaling factor ϵ. The drain of the current mirror transistor 340 couples with the measurable zener diode Z32, such that the test current ϵI_{2t} passes through the measurable zener diode resulting in a voltage drop V_{z32} across the measurable zener diode Z32. The positive input 344a of the determination amplifier 344 couples between the measurable zener diode Z32 and the test current mirror transistor 340 to receive a measured voltage V_m which is proportional to the voltage drop across the measurable zener diode. The negative input 344b of the determination amplifier 344 receives the threshold or sense voltage Vs. The determination amplifier generates an output 346 which is dependent on the voltage level of the measured voltage V_m, and thus dependent on the voltage drop V_{z32} across the measurable zener diode Z32.--